

Notice of References Cited

Application/Control No.

10/628,822

Applicant(s)/Patent Under
Reexamination
WALKER ET AL.

Examiner

SIU M. LEE

Art Unit

2611

Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0198389	10-2004	Alcock et al.	455/456.1
*	B	US-6,006,076	12-1999	Nakamura, Kazumasa	455/186.1
*	C	US-6,741,834	05-2004	Godwin, John P.	455/3.01
*	D	US-5,797,087	08-1998	Lee, Hyo Chan	455/181.1
*	E	US-6,829,475	12-2004	Lee et al.	455/419
*	F	US-2004/0192189	09-2004	Yuhara et al.	455/003.02
*	G	US-4,392,247	07-1983	van Deursen, Theodorus H. M.	455/161.2
*	H	US-5,732,338	03-1998	Schwob, Pierre R.	455/158.5
*	I	US-5,819,166	10-1998	Kimura et al.	455/186.1
*	J	US-7,054,601	05-2006	Heiderscheit et al.	455/179.1
*	K	US-6,163,683	12-2000	Dunn et al.	455/151.1
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U					
	V					
	W					
	X					

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
 Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.